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MPC5777C

MPC5777C Microcontroller Data Sheet

Features

- This document provides electrical specifications, pin assignments, and package diagram information for the MPC5777C series of microcontroller units (MCUs).
- For functional characteristics and the programming model, see the MPC5777C Reference Manual.

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1 Introduction

1.1 Features summary

On-chip modules available within the family include the following features:

- Three dual issue, 32-bit CPU core complexes (e200z7), two of which run in lockstep
  - Power Architecture embedded specification compliance
  - Instruction set enhancement allowing variable length encoding (VLE), optional encoding of mixed 16-bit and 32-bit instructions, for code size footprint reduction
  - On the two computational cores: Signal processing extension (SPE1.1) instruction support for digital signal processing (DSP)
  - Single-precision floating point operations
  - On the two computational cores: 16 KB I-Cache and 16 KB D-Cache
  - Hardware cache coherency between cores
- 16 hardware semaphores
- 3-channel CRC module
- 8 MB on-chip flash memory
  - Supports read during program and erase operations, and multiple blocks allowing EEPROM emulation
- 512 KB on-chip general-purpose SRAM including 64 KB standby RAM
- Two multichannel direct memory access controllers (eDMA)
  - 64 channels per eDMA
- Dual core Interrupt Controller (INTC)
- Dual phase-locked loops (PLLs) with stable clock domain for peripherals and frequency modulation (FM) domain for computational shell
- Crossbar Switch architecture for concurrent access to peripherals, flash memory, or RAM from multiple bus masters with End-To-End ECC
- External Bus Interface (EBI) for calibration and application use
- System Integration Unit (SIU)
- Error Injection Module (EIM) and Error Reporting Module (ERM)
- Four protected port output (PPO) pins
- Boot Assist Module (BAM) supports serial bootload via CAN or SCI
- Three second-generation Enhanced Time Processor Units (eTPUs)
  - 32 channels per eTPU
  - Total of 36 KB code RAM
  - Total of 9 KB parameter RAM

- Enhanced Modular Input/Output System (eMIOS) supporting 32 unified channels with each channel capable of single action, double action, pulse width modulation (PWM) and modulus counter operation
- Two Enhanced Queued Analog-to-Digital Converter (eQADC) modules with:
  - Two separate analog converters per eQADC module
  - Support for a total of 70 analog input pins, expandable to 182 inputs with off-chip multiplexers
  - Interface to twelve hardware Decimation Filters
  - Enhanced "Tap" command to route any conversion to two separate Decimation Filters
- Four independent 16-bit Sigma-Delta ADCs (SDADCs)
- 10-channel Reaction Module
- Ethernet (FEC)
- Two PSI5 modules
- Two SENT Receiver (SRX) modules supporting 12 channels
- Zipwire: SIPI and LFAST modules
- Five Deserial Serial Peripheral Interface (DSPI) modules
- Five Enhanced Serial Communication Interface (eSCI) modules
- Four Controller Area Network (FlexCAN) modules
- Two M_CAN modules that support FD
- Fault Collection and Control Unit (FCCU)
- Clock Monitor Units (CMUs)
- Tamper Detection Module (TDM)
- Cryptographic Services Engine (CSE)
  - Complies with *Secure Hardware Extension (SHE) Functional Specification Version 1.1* security functions
  - Includes software selectable enhancement to key usage flag for MAC verification and increase in number of memory slots for security keys
- PASS module to support security features
- Nexus development interface (NDI) per IEEE-ISTO 5001-2003 standard, with some support for 2010 standard
- Device and board test support per Joint Test Action Group (JTAG) IEEE 1149.1 and 1149.7
- On-chip voltage regulator controller (VRC) that derives the core logic supply voltage from the high-voltage supply
- On-chip voltage regulator for flash memory
- Self Test capability

1.2 Block diagram

The following figure shows a top-level block diagram of the MPC5777C. The purpose of the block diagram is to show the general interconnection of functional modules through the crossbar switch.

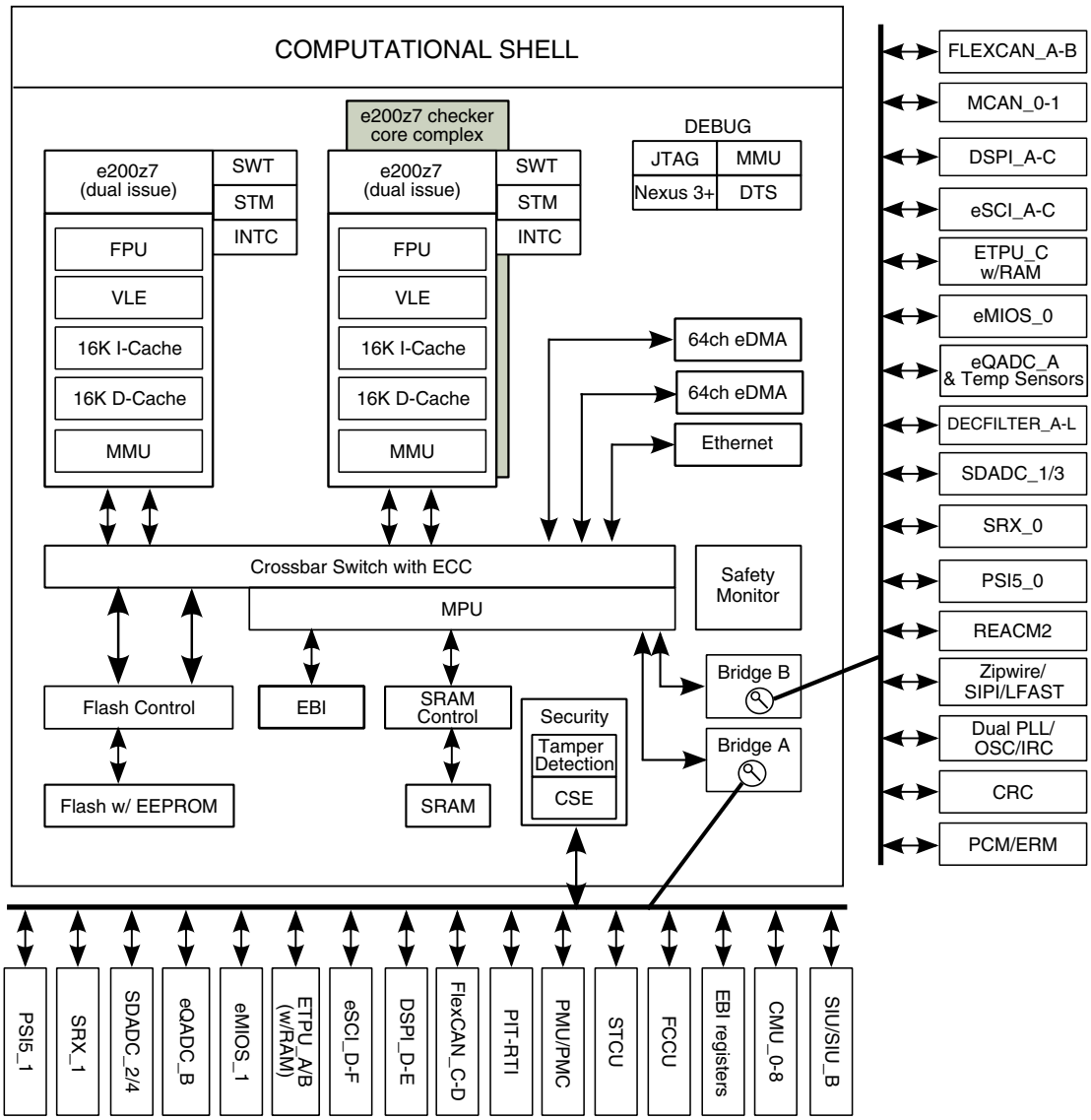

Figure 1. MPC5777C block diagram

2 Pinouts

2.1 416-ball MAPBGA pin assignments

Figure 2 shows the 416-ball MAPBGA pin assignments.

	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18	19	20	21	22	23	24	25	26	
A	VSS	VDD	RSTOUT	ANA0_SDA0	ANA4	ANA8	ANA11	ANA15	VDDA_SD	REFBYPCA25	VRL_SD	VRH_SD	AN28	AN32	AN36	VDDA_EQ	REFBYPCB25	VRL_EQ	VRH_EQ	AN87_SDD7	ANB11	ANB14	ANB17	ANB21	ANB23	VSS	A
B	VDDEH1	VSS	VDD	TEST	ANA1_SDA1	ANA5	ANA10	ANA14	VDDA_MISC	VSSA_SD	REFBYPCA75	AN24	AN27	AN29	AN33	VDDA_EQ	VSSA_EQ	REFBYPCB75	ANB6_SDD6	AN88	ANB10	ANB15	ANB18	ANB22	VSS	TCRCLKC	B
C	ETPUA30	ETPUA31	VSS	VDD	ANA2_SDA2	ANA6	ANA9	ANA13	ANA17_SDB1	ANA19_SDB3	ANA21_SDC1	ANA23_SDC3	AN26	AN30	AN34	AN37	AN38	ANB0_SDD0	ANB4_SDD4	ANB5_SDD5	ANB12	ANB16	ANB19	VSS	ETPUC0	ETPUC1	C
D	ETPUA27	ETPUA28	ETPUA29	VSS	VDD	ANA3_SDA3	ANA7	ANA12	ANA16_SDB0	ANA18_SDB2	ANA20_SDC0	ANA22_SDC2	AN25	AN31	AN35	AN39	ANB1_SDD1	ANB2_SDD2	ANB3_SDD3	ANB9	ANB13	ANB20	VSS	SENT2_A	ETPUC2	ETPUC3	D
E	ETPUA23	ETPUA24	ETPUA25	ETPUA26																			VDDEH7	ETPUC4	ETPUC5	ETPUC6	E
F	ETPUA19	ETPUA20	ETPUA21	ETPUA22																			ETPUC7	ETPUC8	ETPUC9	ETPUC10	F
G	ETPUA15	ETPUA16	ETPUA17	ETPUA18																			ETPUC11	ETPUC12	ETPUC13	ETPUC14	G
H	ETPUA11	ETPUA12	ETPUA14	ETPUA13																			ETPUC15	ETPUC16	ETPUC17	ETPUC18	H
J	ETPUA7	ETPUA8	ETPUA9	ETPUA10																			ETPUC19	ETPUC20	ETPUC21	ETPUC22	J
K	ETPUA3	ETPUA4	ETPUA5	ETPUA6						VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS						ETPUC23	ETPUC24	ETPUC25	ETPUC26	K
L	TCRCLKA	ETPUA0	ETPUA1	ETPUA2						VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS						ETPUC27	ETPUC28	ETPUC29	ETPUC30	L
M	NC	TXDA	RXDA	VSTBY						VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS						ETPUC31	ETPUB15	ETPUB14	VDDEH7	M
N	RXDB	BOOTCFG1	WKPCFG	VDD						VDDE2	VSS	VSS	VSS	VSS	VSS	VSS	VSS						VDDEH6	ETPUB11	ETPUB12	ETPUB13	N
P	TXDB	PLLCFG1	PLLCFG2	VDDEH1						VDDE2	VDDE2	VSS	VSS	VSS	VSS	VSS	VSS						ETPUB7	ETPUB8	ETPUB9	ETPUB10	P
R	JCOMP	RESET	PLLCFG0	RDY						VDDE2	VDDE2	VSS	VSS	VSS	VSS	VSS	VSS						ETPUB3	ETPUB4	ETPUB5	ETPUB6	R
T	VDDE2	MCKO	MSEO1	EVTI						VDDE2	VDDE2	VDDE2	VSS	VSS	VSS	VSS	VSS						TCRCLKB	ETPUB0	ETPUB1	ETPUB2	T
U	EVTO	MSEO0	MDO0	MDO1						VDDE2	VDDE2	VDDE2	VSS	VSS	VSS	VSS	VSS						ETPUB19	ETPUB18	ETPUB17	ETPUB16	U
V	MDO2	MDO3	MDO4	MDO5																			ETPUB26	ETPUB22	ETPUB21	ETPUB20	V
W	MDO6	MDO7	MDO8	VDDE2																			REGSEL	ETPUB25	ETPUB24	ETPUB23	W
Y	MDO9	MDO10	MDO11	MDO15																			ETPUB29	ETPUB28	ETPUB27	REGCTL	Y
AA	MDO12	MDO13	MDO14	NC																			VDDPMC	ETPUB30	VDDPWR	VSSSYN	AA
AB	TDO	TCK	TMS	VDD																			VDD	ETPUB31	VSSPWR	EXTAL	AB
AC	VDDE2	TDI	VDD	VSS	FEC_TXCLK_REFCLK	PCSA1	PCSA2	PCSB4	PCSB1	VDDEH3	VDDEH4	VDD	EMIOS8	EMIOS14	EMIOS18	EMIOS22	EMIOS27	EMIOS31	CNRXB	CNRXD	VDDEH5	PCSC1	VSSPMC	VDD	VDDEH6	XTAL	AC
AD	ENGCLK	VDD	VSS	FEC_TXD0	FEC_TXD1	PCSA5	SOUTA	SCKA	PCSB0	PCSB3	EMIOS2	EMIOS5	EMIOS9	EMIOS15	EMIOS19	EMIOS23	EMIOS26	EMIOS30	CNTXB	CNTXD	SCKC	RXDC	PCSC3	VSS	VDD	VDDFLA	AD
AE	VDD	VSS	FEC_RX_DV	FEC_TX_EN	PCSA4	PCSA0	PCSA3	SCKB	SINB	EMIOS0	EMIOS3	EMIOS6	EMIOS10	EMIOS13	EMIOS17	EMIOS21	EMIOS25	EMIOS29	CNRXA	CNRXC	PCSC0	SINC	PCSC2	PCSC5	VSS	VDD	AE
AF	VSS	VDDE2A	FEC_RXD0	FEC_RXD1	VDDEH3A	PCSB5	SINA	PCSB2	SOUTB	EMIOS1	EMIOS4	EMIOS7	EMIOS11	EMIOS12	EMIOS16	EMIOS20	EMIOS24	EMIOS28	CNTXA	CNTXC	SOUTC	VDDEH4	TXDC	PCSC4	VDDEH5	VSS	AF
	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18	19	20	21	22	23	24	25	26	

Figure 2. MPC5777C 416-ball MAPBGA (full diagram)

2.2 516-ball MAPBGA pin assignments

Figure 3 shows the 516-ball MAPBGA pin assignments.

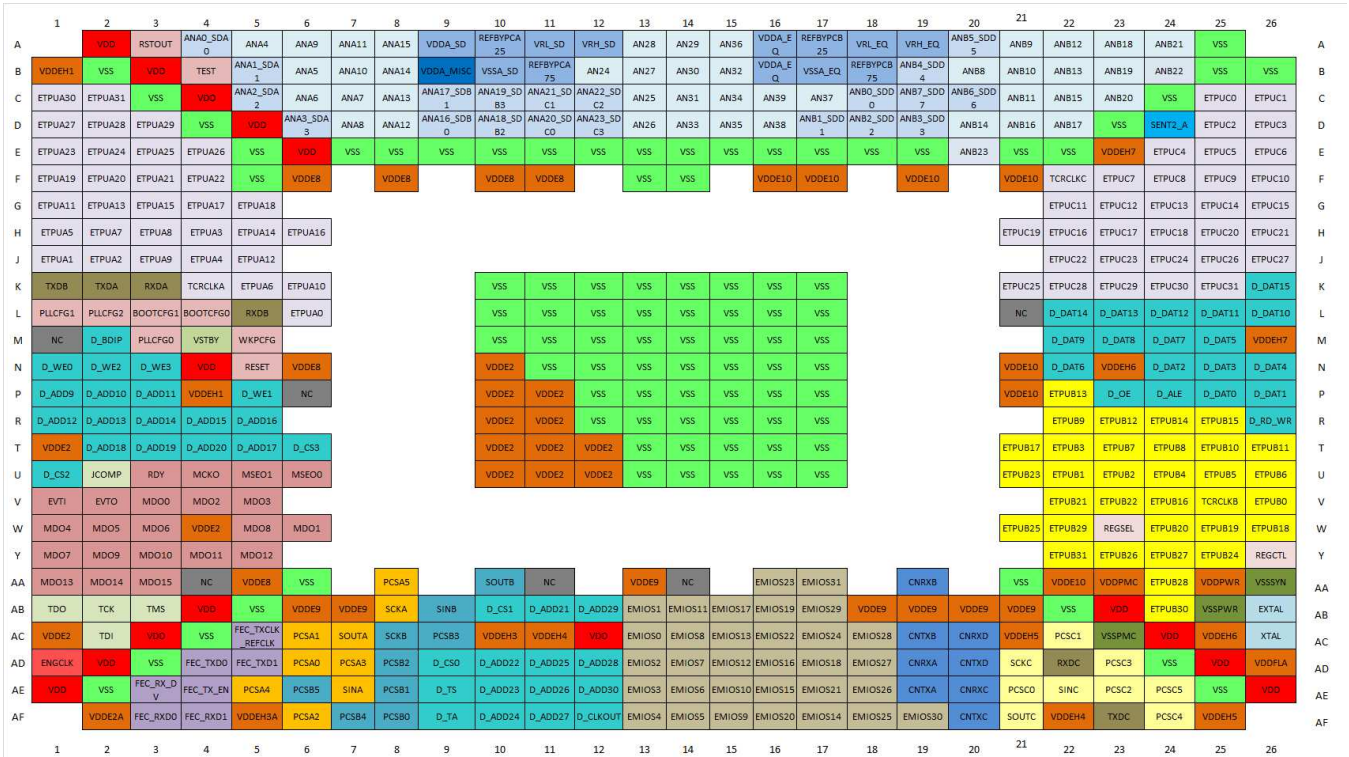

Figure 3. MPC5777C 516-ball MAPBGA (full diagram)

3 Electrical characteristics

The following information includes details about power considerations, DC/AC electrical characteristics, and AC timing specifications.

3.1 Absolute maximum ratings

Absolute maximum specifications are stress ratings only. Functional operation at these maxima is not guaranteed.

CAUTION

Stress beyond listed maxima may affect device reliability or cause permanent damage to the device.

See Operating conditions for functional operation specifications.

Table 1. Absolute maximum ratings

Symbol	Parameter	Conditions[1]	Value		Unit
			Min	Max	
Cycle	Lifetime power cycles	—	—	1000k	—
V_{DD}	1.2 V core supply voltage[2, 3, 4]	—	–0.3	1.5	V
V_{DDEHx}	I/O supply voltage (medium I/O pads)[5]	—	–0.3	6.0	V
V_{DDEx}	I/O supply voltage (fast I/O pads)[5]	—	–0.3	6.0	V
V_{DDPMC}	Power Management Controller supply voltage[5]	—	–0.3	6.0	V
V_{DDFLA}	Decoupling pin for flash regulator[6]	—	–0.3	4.5	V
V_{STBY}	RAM standby supply voltage[5]	—	–0.3	6.0	V
V_{SSA_SD}	SDADC ground voltage	Reference to V_{SS}	–0.3	0.3	V
V_{SSA_EQ}	eQADC ground voltage	Reference to V_{SS}	–0.3	0.3	V
$V_{DDA\_EQA/B}$	eQADC supply voltage	Reference to V_{SSA_EQ}	–0.3	6.0	V
V_{DDA_SD}	SDADC supply voltage	Reference to V_{SSA_SD}	–0.3	6.0	V
V_{RL_SD}	SDADC ground reference	Reference to V_{SS}	–0.3	0.3	V
V_{RL_EQ}	eQADC ground reference	Reference to V_{SS}	–0.3	0.3	V
V_{RH_EQ}	eQADC alternate reference	Reference to V_{RL_EQ}	–0.3	6.0	V
V_{RH_SD}	SDADC alternate reference	Reference to V_{RL_SD}	–0.3	6.0	V
$V_{REFBYPC}$	eQADC reference decoupling capacitor pins	REFBYPCA25, REFBYPCA75, REFBYPCB25, REFBYPC75	–0.3	6.0	V
V_{DDA_MISC}	TRNG and IRC supply voltage	—	–0.3	6.0	V
V_{DDPWR}	SMPS driver supply pin	—	–0.3	6.0	V
V_{SSPWR}	SMPS driver supply pin	Reference to V_{SS}	–0.3	0.3	V
$V_{SS} – V_{SSA\_EQ}$	V_{SSA_EQ} differential voltage	—	–0.3	0.3	V
$V_{SS} – V_{SSA\_SD}$	V_{SSA_SD} differential voltage	—	–0.3	0.3	V
$V_{SS} – V_{RL\_EQ}$	V_{RL_EQ} differential voltage	—	–0.3	0.3	V
$V_{SS} – V_{RL\_SD}$	V_{RL_SD} differential voltage	—	–0.3	0.3	V
V_{IN}	I/O input voltage range[7]	—	–0.3	6.0	V
		Relative to V_{DDEx}/V_{DDEHx}	—	0.3	V
		Relative to V_{SS}	–0.3	—	V
I_{INJD}	Maximum DC injection current for digital pad	Per pin, applies to all digital pins	–5	5	mA
I_{INJA}	Maximum DC injection current for analog pad	Per pin, applies to all analog pins	–5	5	mA
I_{MAXSEG}[8, 9]	Maximum current per I/O power segment	—	–120	120	mA
T_{STG}	Storage temperature range and non-operating times	—	–55	175	°C
STORAGE	Maximum storage time, assembled part programmed in ECU	No supply; storage temperature in range –40 °C to 60 °C	—	20	years
T_{SDR}	Maximum solder temperature[10] Pb-free package	—	—	260	°C

Table continues on the next page...

Table 1. Absolute maximum ratings (continued)

Symbol	Parameter	Conditions[1]	Value		Unit
			Min	Max	
MSL	Moisture sensitivity level[11]	—	—	3	—

1. Voltages are referred to V_{SS} if not specified otherwise
2. Allowed 1.45 V – 1.5 V for 60 seconds cumulative time at maximum T_J = 150 °C; remaining time as defined in note 3 and note 4
3. Allowed 1.375 V – 1.45 V for 10 hours cumulative time at maximum T_J = 150 °C; remaining time as defined in note 4
4. 1.32 V – 1.375 V range allowed periodically for supply with sinusoidal shape and average supply value below 1.275 V at maximum T_J = 150 °C
5. Allowed 5.5 V – 6.0 V for 60 seconds cumulative time with no restrictions, for 10 hours cumulative time device in reset, T_J = 150 °C; remaining time at or below 5.5 V
6. Allowed 3.6 V – 4.5 V for 60 seconds cumulative time with no restrictions, for 10 hours cumulative time device in reset, T_J = 150 °C; remaining time at or below 3.6 V
7. The maximum input voltage on an I/O pin tracks with the associated I/P supply maximum. For the injection current condition on a pin, the voltage will be equal to the supply plus the voltage drop across the internal ESD diode from I/O pin to supply. The diode voltage varies greatly across process and temperature, but a value of 0.3V can be used for nominal calculations.
8. The sum of all controller pins (including both digital and analog) must not exceed 200 mA. A V_{DDEx}/V_{DDEHx} power segment is defined as one or more GPIO pins located between two V_{DDEx}/V_{DDEHx} supply pins.
9. The average current values given in I/O pad current specifications should be used to calculate total I/O segment current.
10. Solder profile per IPC/JEDEC J-STD-020D
11. Moisture sensitivity per JEDEC test method A112

3.2 Electromagnetic interference (EMI) characteristics

Test reports with EMC measurements to IC-level IEC standards are available on request.

To find application notes that provide guidance on designing your system to minimize interference from radiated emissions, go to nxp.com and perform a keyword search for "radiated emissions."

3.3 Electrostatic discharge (ESD) characteristics

Table 2. ESD Ratings[1, 2]

Symbol	Parameter	Conditions	Value	Unit
V_{HBM}	ESD for Human Body Model (HBM)	All pins	2000	V
V_{CDM}	ESD for Charged Device Model (CDM)	Corner pins	750	V
		Non-corner pins	500	

1. All ESD testing is in conformity with CDF-AEC-Q100 Stress Test Qualification for Automotive Grade Integrated Circuits.
2. A device will be defined as a failure if after exposure to ESD pulses the device no longer meets the device specification requirements.

3.4 Operating conditions

The following table describes the operating conditions for the device, and for which all specifications in the data sheet are valid, except where explicitly noted.

If the device operating conditions are exceeded, the functionality of the device is not guaranteed.

Table 3. Device operating conditions

Symbol	Parameter	Conditions	Value			Unit
			Min	Typ	Max	
Frequency						
f_{SYS}	Device operating frequency[1]	—	—	—	264[2]	MHz
f_{PLATF}	Platform operating frequency	—	—	—	132	MHz
f_{ETPU}	eTPU operating frequency	—	—	—	200	MHz
f_{EBI}	EBI operating frequency	—	—	—	66	MHz
f_{PER}	Peripheral block operating frequency	—	—	—	132	MHz
f_{FM_PER}	Frequency-modulated peripheral block operating frequency	—	—	—	132	MHz
t_{CYC}	Platform clock period	—	—	—	$1/f_{PLATF}$	ns
t_{CYC_ETPU}	eTPU clock period	—	—	—	$1/f_{ETPU}$	ns
t_{CYC_PER}	Peripheral clock period	—	—	—	$1/f_{PER}$	ns
Temperature						
T_J	Junction operating temperature range	Packaged devices	–40.0	—	150.0	°C
T_A (T_L to T_H)	Ambient operating temperature range	Packaged devices	–40.0	—	125.0[3]	°C
Voltage						
V_{DD}	External core supply voltage[4, 5]	LVD/HVD enabled	1.2	—	1.32	V
		LVD/HVD disabled[6, 7, 8, 9]	1.2	—	1.38	
V_{DDA_MISC}	TRNG and IRC supply voltage	—	3.5	—	5.5	V
V_{DDEx}	I/O supply voltage (fast I/O pads)	5 V range	4.5	—	5.5	V
		3.3 V range	3.0	—	3.6	
V_{DDEHx}[9]	I/O supply voltage (medium I/O pads)	5 V range	4.5	—	5.5	V
		3.3 V range	3.0	—	3.6	
V_{DDEH1}	eTPU_A, eSCI_A, eSCI_B, and configuration I/O supply voltage (medium I/O pads)	5 V range	4.5	—	5.5	V
V_{DDPMC}[10]	Power Management Controller (PMC) supply voltage	Full functionality	3.15	—	5.5	V
V_{DDPWR}	SMPS driver supply voltage	Reference to V_{SSPWR}	3.0	—	5.5	V
V_{DDFLA}	Flash core voltage	—	3.15	—	3.6	V
V_{STBY}	RAM standby supply voltage	—	0.95[11]	—	5.5	V

Table continues on the next page...

Table 3. Device operating conditions (continued)

Symbol	Parameter	Conditions	Value			Unit
			Min	Typ	Max	
V_{STBY_BO}	Standby RAM brownout flag trip point voltage	—	—	—	0.9[12]	V
V_{RL_SD}	SDADC ground reference voltage	—	V_{SSA_SD}			V
V_{DDA_SD}	SDADC supply voltage[13]	—	4.5	—	5.5	V
$V_{DDA\_EQA/B}$	eQADC supply voltage	—	4.75	—	5.25	V
V_{RH_SD}	SDADC reference	—	4.5	V_{DDA_SD}	5.5	V
$V_{DDA\_SD} - V_{RH\_SD}$	SDADC reference differential voltage	—	—	—	25	mV
$V_{SSA\_SD} - V_{RL\_SD}$	V_{RL_SD} differential voltage	—	–25	—	25	mV
V_{RH_EQ}	eQADC reference	—	4.75	—	5.25	V
$V_{DDA\_EQA/B} - V_{RH\_EQ}$	eQADC reference differential voltage	—	—	—	25	mV
$V_{SSA\_EQ} - V_{RL\_EQ}$	V_{RL_EQ} differential voltage	—	–25	—	25	mV
$V_{SSA\_EQ} - V_{SS}$	V_{SSA_EQ} differential voltage	—	–25	—	25	mV
$V_{SSA\_SD} - V_{SS}$	V_{SSA_SD} differential voltage	—	–25	—	25	mV
V_{RAMP}	Slew rate on power supply pins	—	—	—	100	V/ms
Current						
I_{IC}	DC injection current (per pin)[14, 15, 16]	Digital pins and analog pins	–3.0	—	3.0	mA
I_{MAXSEG}	Maximum current per power segment[17, 18]	—	–80	—	80	mA

1. Maximum operating frequency is applicable to the computational cores and platform for the device. See the Clocking chapter in the MPC5777C Microcontroller Reference Manual for more information on the clock limitations for the various IP blocks on the device.
2. If frequency modulation (FM) is enabled, the maximum frequency still cannot exceed this value.
3. The maximum specification for operating junction temperature T_J must be respected. Thermal characteristics provides details.
4. Core voltage as measured on device pin to guarantee published silicon performance
5. During power ramp, voltage measured on silicon might be lower. Maximum performance is not guaranteed, but correct silicon operation is guaranteed. See power management and reset management for description.
6. Maximum core voltage is not permitted for entire product life. See absolute maximum rating.
7. When internal LVD/HVDs are disabled, external monitoring is required to guarantee device operation. Failure to monitor externally supply voltage may result in erroneous operation of the device.
8. This LVD/HVD disabled supply voltage condition only applies after LVD/HVD are disabled by the application during the reset sequence, and the LVD/HVD are active until that point.
9. This spec does not apply to V_{DDEH1}.
10. When internal flash memory regulator is used:
    - Flash memory read operation is supported for a minimum V_{DDPMC} value of 3.15 V.
    - Flash memory read, program, and erase operations are supported for a minimum V_{DDPMC} value of 3.5 V.

    When flash memory power is supplied externally (V_{DDPMC} shorted to V_{DDFLA}): The V_{DDPMC} range must be within the limits specified for LVD_FLASH and HVD_FLASH monitoring. Table 29 provides the monitored LVD_FLASH and HVD_FLASH limits.
11. If the standby RAM regulator is not used, the V_{STBY} supply input pin must be tied to ground.
12. V_{STBY_BO} is the maximum voltage that sets the standby RAM brownout flag in the device logic. The minimum voltage for RAM data retention is guaranteed always to be less than the V_{STBY_BO} maximum value.

13. For supply voltages between 3.0 V and 4.0 V there will be no guaranteed precision of ADC (accuracy/linearity). ADC will recover to a fully functional state when the voltage rises above 4.0 V.
14. Full device lifetime without performance degradation
15. I/O and analog input specifications are only valid if the injection current on adjacent pins is within these limits. See the absolute maximum ratings table for maximum input current for reliability requirements.
16. The I/O pins on the device are clamped to the I/O supply rails for ESD protection. When the voltage of the input pin is above the supply rail, current will be injected through the clamp diode to the supply rail. For external RC network calculation, assume a typical 0.3 V drop across the active diode. The diode voltage drop varies with temperature.
17. The sum of all controller pins (including both digital and analog) must not exceed 200 mA. A V_{DDEx}/V_{DDEHx} power segment is defined as one or more GPIO pins located between two V_{DDEx}/V_{DDEHx} supply pins.
18. The average current values given in I/O pad current specifications should be used to calculate total I/O segment current.

3.5 DC electrical specifications

NOTE

I_{DDA_MISC} is the sum of current consumption of IRC, I_{TRNG}, and I_{STBY} in the 5 V domain. IRC current is provided in the IRC specifications.

NOTE

I/O, XOSC, EQADC, SDADC, and Temperature Sensor current specifications are in those components' dedicated sections.

Table 4. DC electrical specifications

Symbol	Parameter	Conditions	Value			Unit
			Min	Typ	Max	
I_{DD}	Operating current on the V_{DD} core logic supply[1]	LVD/HVD enabled, V_{DD} = 1.2 V to 1.32 V	—	0.65	1.35	A
		LVD/HVD disabled, V_{DD} = 1.2 V to 1.38 V	—	0.65	1.4	
I_{DD_PE}	Operating current on the V_{DD} supply for flash memory program/erase	—	—	—	85	mA
I_{DDPMC}	Operating current on the V_{DDPMC} supply[2]	Flash memory read	—	—	40	mA
		Flash memory program/erase	—	—	70	
		PMC only	—	—	35	
	Operating current on the V_{DDPMC} supply (internal core regulator bypassed)	Flash memory read	—	—	10	mA
		Flash memory program/erase	—	—	40	
		PMC only	—	—	5	
I_{REGCTL}	Core regulator DC current output on V_{REGCTL} pin	—	—	—	25	mA
I_{STBY}	Standby RAM supply current (T_J = 150°C)	1.08 V	—	—	1140	µA
		1.25 V to 5.5 V	—	—	1170	
I_{DD_PWR}	Operating current on the V_{DDPWR} supply	—	—	—	50	mA
I_{BG_REF}	Bandgap reference current consumption[3]		—	—	600	µA
I_{TRNG}	True Random Number Generator current	—	—	—	2.1	mA

1. I_{DD} measured on an application-specific pattern with all cores enabled at full frequency, T_J = 40°C to 150°C. Flash memory program/erase current on the V_{DD} supply not included.
2. This value is considering the use of the internal core regulator with the simulation of an external transistor with the minimum value of h_{FE} of 60.
3. This bandgap reference is for EQADC calibration and Temperature Sensors.

3.6 I/O pad specifications

The following table describes the different pad types on the chip.

Table 5. I/O pad specification descriptions

Pad type	Description
General-purpose I/O pads	General-purpose I/O and EBI data bus pads with four selectable output slew rate settings; also called SR pads
EBI pads	Provide necessary speed for fast external memory interfaces on the EBI CLKOUT, address, and control signals; also called FC pads
LVDS pads	Low Voltage Differential Signal interface pads
Input-only pads	Low-input-leakage pads that are associated with the ADC channels

NOTE

Each I/O pin on the device supports specific drive configurations. See the signal description table in the device reference manual for the available drive configurations for each I/O pin.

NOTE

Throughout the I/O pad specifications, the symbol V_{DDEx} represents all V_{DDEx} and V_{DDEHx} segments.

3.6.1 Input pad specifications

Table 6 provides input DC electrical characteristics as described in Figure 4.

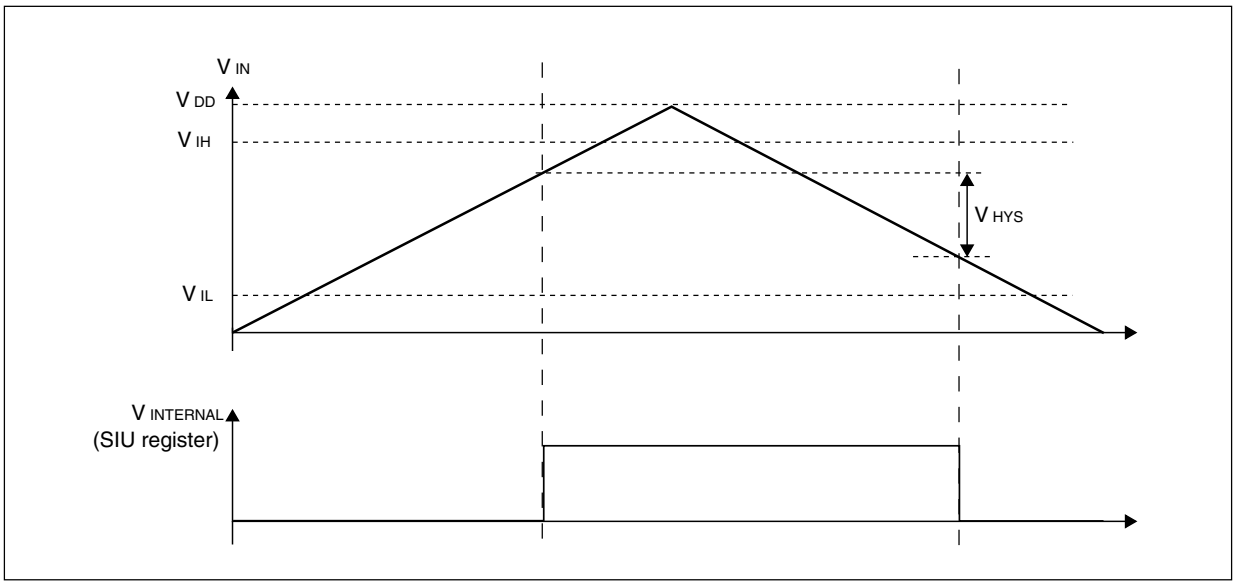

Figure 4. I/O input DC electrical characteristics definition

Table 6. I/O input DC electrical characteristics

Symbol	Parameter	Conditions	Value			Unit
			Min	Typ	Max	
V_{IHCMOS_H}	Input high level CMOS (with hysteresis)	3.0 V < V_{DDEx} < 3.6 V and 4.5 V < V_{DDEx} < 5.5 V	0.65 * V_{DDEx}	—	V_{DDEx} + 0.3	V
V_{IHCMOS}	Input high level CMOS (without hysteresis)	3.0 V < V_{DDEx} < 3.6 V and 4.5 V < V_{DDEx} < 5.5 V	0.55 * V_{DDEx}	—	V_{DDEx} + 0.3	V
V_{ILCMOS_H}	Input low level CMOS (with hysteresis)	3.0 V < V_{DDEx} < 3.6 V and 4.5 V < V_{DDEx} < 5.5 V	–0.3	—	0.35 * V_{DDEx}	V
V_{ILCMOS}	Input low level CMOS (without hysteresis)	3.0 V < V_{DDEx} < 3.6 V and 4.5 V < V_{DDEx} < 5.5 V	–0.3	—	0.4 * V_{DDEx}	V
$V_{HYSCMOS}$	Input hysteresis CMOS	3.0 V < V_{DDEx} < 3.6 V and 4.5 V < V_{DDEx} < 5.5 V	0.1 * V_{DDEx}	—	—	V
Input Characteristics[1]						
I_{LKG}	Digital input leakage	V_{SS} < V_{IN} < V_{DDEx}/V_{DDEHx}	—	—	2.5	µA
I_{LKG_FAST}	Digital input leakage for EBI address/control signal pads	V_{SS} < V_{IN} < V_{DDEx}/V_{DDEHx}	—	—	2.5	µA
I_{LKGA}	Analog pin input leakage (5 V range)	V_{SSA_SD} < V_{IN} < V_{DDA_SD}, V_{SSA_EQ} < V_{IN} < $V_{DDA\_EQA/B}$	—	—	220	nA
C_{IN}	Digital input capacitance	GPIO and EBI input pins	—	—	7	pF

1. For LFAST, microsecond bus, and LVDS input characteristics, see dedicated communication module sections.

Table 7 provides current specifications for weak pullup and pulldown.

Table 7. I/O pullup/pulldown DC electrical characteristics

Symbol	Parameter	Conditions	Value			Unit
			Min	Typ	Max	
I_{WPU}	Weak pullup current	V_{IN} = 0.35 * V_{DDEx} 4.5 V < V_{DDEx} < 5.5 V	40	—	120	µA
		V_{IN} = 0.35 * V_{DDEx} 3.0 V < V_{DDEx} < 3.6 V	25	—	80	
I_{WPD}	Weak pulldown current	V_{IN} = 0.65 * V_{DDEx} 4.5 V < V_{DDEx} < 5.5 V	40	—	120	µA
		V_{IN} = 0.65 * V_{DDEx} 3.0 V < V_{DDEx} < 3.6 V	25	—	80	

The specifications in Table 8 apply to the pins ANA0_SDA0 to ANA7, ANA16_SDB0 to ANA23_SDC3, and ANB0_SDD0 to ANB7_SDD7.

Table 8. I/O pullup/pulldown resistance electrical characteristics

Symbol	Parameter	Conditions	Value			Unit
			Min	Typ	Max	
R_{PUPD}	Analog input bias / diagnostic pullup/ pulldown resistance	200 kΩ	130	200	280	kΩ
		100 kΩ	65	100	140	
		5 kΩ	1.4	5	7.5	
Δ_{PUPD}	R_{PUPD} pullup/pulldown resistance mismatch	—	—	—	5	%

3.6.2 Output pad specifications

Figure 5 shows output DC electrical characteristics.

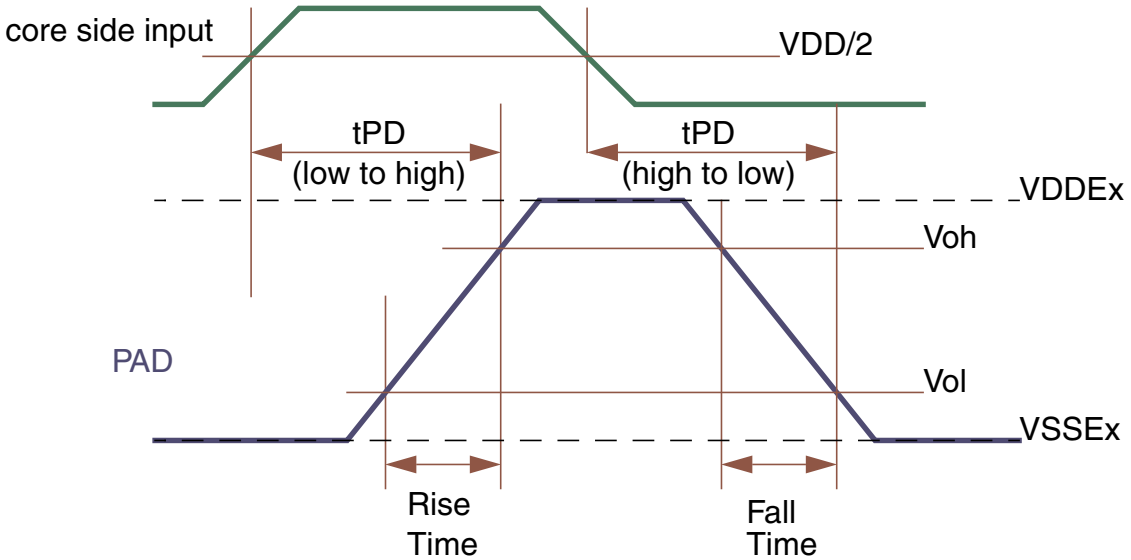

Figure 5. I/O output DC electrical characteristics definition

The following tables specify output DC electrical characteristics.

Table 9. GPIO and EBI data pad output buffer electrical characteristics (SR pads)[1]

Symbol	Parameter	Conditions[2]		Value[3]			Unit
				Min	Typ	Max	
I_{OH}	GPIO pad output high current	V_{OH} = 0.8 * V_{DDEx}	PCR[SRC] = 11b or 01b	25	—	—	mA
		4.5 V < V_{DDEx} < 5.5 V	PCR[SRC] = 10b or 00b	15	—	—	
		V_{OH} = 0.8 * V_{DDEx}	PCR[SRC] = 11b or 01b	13	—	—	
		3.0 V < V_{DDEx} < 3.6 V	PCR[SRC] = 10b or 00b	8	—	—	
I_{OL}	GPIO pad output low current	V_{OL} = 0.2 * V_{DDEx}	PCR[SRC] = 11b or 01b	48	—	—	mA
		4.5 V < V_{DDEx} < 5.5 V	PCR[SRC] = 10b or 00b	22	—	—	
		V_{OL} = 0.2 * V_{DDEx}	PCR[SRC] = 11b or 01b	17	—	—	
		3.0 V < V_{DDEx} < 3.6 V	PCR[SRC] = 10b or 00b	10.5	—	—	

Table continues on the next page...

Table 9. GPIO and EBI data pad output buffer electrical characteristics (SR pads)[1] (continued)

Symbol	Parameter	Conditions[2]		Value[3]			Unit
				Min	Typ	Max	
t_{R_F}	GPIO pad output transition time (rise/fall)	PCR[SRC] = 11b	C_L = 25 pF	—	—	1.2	ns
		4.5 V < V_{DDEx} < 5.5 V	C_L = 50 pF	—	—	2.5	
			C_L = 200 pF	—	—	8	
		PCR[SRC] = 11b	C_L = 25 pF	—	—	1.7	
		3.0 V < V_{DDEx} < 3.6 V	C_L = 50 pF	—	—	3.25	
			C_L = 200 pF	—	—	12	
		PCR[SRC] = 10b	C_L = 50 pF	—	—	5	
		4.5 V < V_{DDEx} < 5.5 V	C_L = 200 pF	—	—	18	
		PCR[SRC] = 10b	C_L = 50 pF	—	—	7	
		3.0 V < V_{DDEx} < 3.6 V	C_L = 200 pF	—	—	25	
		PCR[SRC] = 01b	C_L = 50 pF	—	—	13	
		4.5 V < V_{DDEx} < 5.5 V	C_L = 200 pF	—	—	24	
		PCR[SRC] = 01b	C_L = 50 pF	—	—	25	
		3.0 V < V_{DDEx} < 3.6 V	C_L = 200 pF	—	—	30	
		PCR[SRC] = 00b	C_L = 50 pF	—	—	24	
		4.5 V < V_{DDEx} < 5.5 V	C_L = 200 pF	—	—	50	
		PCR[SRC] = 00b	C_L = 50 pF	—	—	40	
		3.0 V < V_{DDEx} < 3.6 V	C_L = 200 pF	—	—	51	
t_{PD}	GPIO pad output propagation delay time	PCR[SRC] = 11b	C_L = 50 pF	—	—	6	ns
		4.5 V < V_{DDEx} < 5.5 V	C_L = 200 pF	—	—	13	
		PCR[SRC] = 11b	C_L = 50 pF	—	—	8.25	
		3.0 V < V_{DDEx} < 3.6 V	C_L = 200 pF	—	—	19.5	
		PCR[SRC] = 10b	C_L = 50 pF	—	—	9	
		4.5 V < V_{DDEx} < 5.5 V	C_L = 200 pF	—	—	22	
		PCR[SRC] = 10b	C_L = 50 pF	—	—	12.5	
		3.0 V < V_{DDEx} < 3.6 V	C_L = 200 pF	—	—	35	
		PCR[SRC] = 01b	C_L = 50 pF	—	—	27	
		4.5 V < V_{DDEx} < 5.5 V	C_L = 200 pF	—	—	40	
		PCR[SRC] = 01b	C_L = 50 pF	—	—	45	
		3.0 V < V_{DDEx} < 3.6 V	C_L = 200 pF	—	—	65	
		PCR[SRC] = 00b	C_L = 50 pF	—	—	40	
		4.5 V < V_{DDEx} < 5.5 V	C_L = 200 pF	—	—	65	
		PCR[SRC] = 00b	C_L = 50 pF	—	—	75	
		3.0 V < V_{DDEx} < 3.6 V	C_L = 200 pF	—	—	100	
$\lvert t_{SKEW\_W} \rvert$	Difference between rise and fall time	—		—	—	25	%

1. All GPIO pad output specifications are valid for 3.0 V < V_{DDEx} < 5.5 V, except where explicitly stated.

2. PCR[SRC] values refer to the setting of that register field in the SIU.
3. All values to be confirmed during device validation.

The following table shows the EBI CLKOUT, address, and control signal pad electrical characteristics. These pads can also be used for GPIO.

Table 10. GPIO and EBI CLKOUT, address, and control signal pad output buffer electrical characteristics (FC pads)

Symbol	Parameter	Conditions[1]		Value			Unit
				Min	Typ	Max	
EBI Mode Output Specifications: valid for 3.0 V < V_{DDEx} < 3.6 V							
C_{DRV}	External bus load capacitance	PCR[DSC] = 01b		—	—	10	pF
		PCR[DSC] = 10b		—	—	20	
		PCR[DSC] = 11b		—	—	30	
f_{MAX_EBI}	External bus maximum operating frequency	C_{DRV} = 10/20/30 pF		—	—	66	MHz
GPIO and EBI Mode Output Specifications							
I_{OH_EBI}	GPIO and external bus pad output high current	V_{OH} = 0.8 * V_{DDEx} 4.5 V < V_{DDEx} < 5.5 V	PCR[DSC] = 11b	30	—	—	mA
			PCR[DSC] = 10b	22	—	—	
			PCR[DSC] = 01b	13	—	—	
			PCR[DSC] = 00b	2	—	—	
		V_{OH} = 0.8 * V_{DDEx} 3.0 V < V_{DDEx} < 3.6 V	PCR[DSC] = 11b	16	—	—	
			PCR[DSC] = 10b	12	—	—	
			PCR[DSC] = 01b	7	—	—	
			PCR[DSC] = 00b	1	—	—	
I_{OL_EBI}	GPIO and external bus pad output low current	V_{OL} = 0.2 * V_{DDEx} 4.5 V < V_{DDEx} < 5.5 V	PCR[DSC] = 11b	54	—	—	mA
			PCR[DSC] = 10b	25	—	—	
			PCR[DSC] = 01b	16	—	—	
			PCR[DSC] = 00b	2	—	—	
		V_{OL} = 0.2 * V_{DDEx} 3.0 V < V_{DDEx} < 3.6 V	PCR[DSC] = 11b	17	—	—	
			PCR[DSC] = 10b	14	—	—	
			PCR[DSC] = 01b	8	—	—	
			PCR[DSC] = 00b	1	—	—	
$t_{R\_F\_EBI}$	GPIO and external bus pad output transition time (rise/fall)	PCR[DSC] = 11b	C_L = 30 pF	—	—	1.5	ns
			C_L = 50 pF	—	—	2.4	
		PCR[DSC] = 10b	C_L = 20 pF	—	—	1.5	
		PCR[DSC] = 01b	C_L = 10 pF	—	—	1.85	
		PCR[DSC] = 00b	C_L = 50 pF	—	—	45	
t_{PD_EBI}	GPIO and external bus pad output propagation delay time	PCR[DSC] = 11b	C_L = 30 pF	—	—	4.2	ns
			C_L = 50 pF	—	—	5.5	
		PCR[DSC] = 10b	C_L = 20 pF	—	—	4.2	
		PCR[DSC] = 01b	C_L = 10 pF	—	—	4.4	
		PCR[DSC] = 00b	C_L = 50 pF	—	—	59	

1. PCR[DSC] values refer to the setting of that register field in the SIU.

3.6.3 I/O pad current specifications

The I/O pads are distributed across the I/O supply segments. Each I/O supply segment is associated with a V_{DDEx} supply segment.

Table 11 provides I/O consumption figures.

To ensure device reliability, the average current of the I/O on a single segment should remain below the I_{MAXSEG} value given in Table 1.

To ensure device functionality, the average current of the I/O on a single segment should remain below the I_{MAXSEG} value given in Table 3.

NOTE

The MPC5777C I/O Signal Description and Input Multiplexing Tables are contained in a Microsoft Excel® file attached to the Reference Manual. In the spreadsheet, select the I/O Signal Table tab.

Table 11. I/O consumption

Symbol	Parameter	Conditions	Value			Unit
			Min	Typ	Max	
I_{AVG_GPIO}	Average I/O current for GPIO pads (per pad)	C_L = 25 pF, 2 MHz V_{DDEx} = 5.0 V ± 10%	—	—	0.42	mA
		C_L = 50 pF, 1 MHz V_{DDEx} = 5.0 V ± 10%	—	—	0.35	
I_{AVG_EBI}	Average I/O current for external bus output pins (per pad)	C_{DRV} = 10 pF, f_{EBI} = 66 MHz V_{DDEx} = 3.3 V ± 10%	—	—	9	mA
		C_{DRV} = 20 pF, f_{EBI} = 66 MHz V_{DDEx} = 3.3 V ± 10%	—	—	18	
		C_{DRV} = 30 pF, f_{EBI} = 66 MHz V_{DDEx} = 3.3 V ± 10%	—	—	30	

3.7 Oscillator and PLL electrical specifications

The on-chip dual PLL—consisting of the peripheral clock and reference PLL (PLL0) and the frequency-modulated system PLL (PLL1)—generates the system and auxiliary clocks from the main oscillator driver.

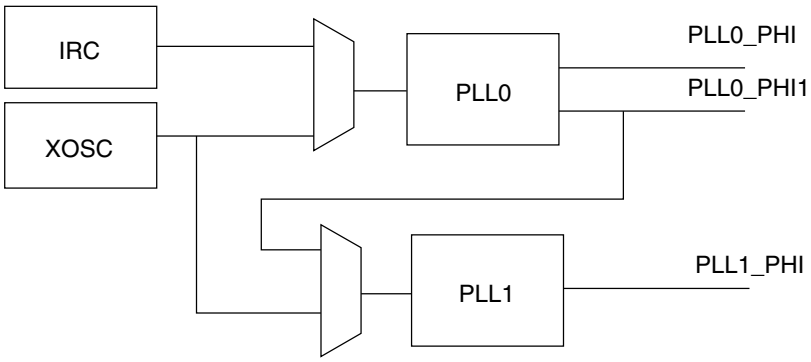

Figure 6. PLL integration

3.7.1 PLL electrical specifications

Table 12. PLL0 electrical characteristics

Symbol	Parameter	Conditions	Value			Unit
			Min	Typ	Max	
f_{PLL0IN}	PLL0 input clock[1, 2]	—	8	—	44	MHz
Δ_{PLL0IN}	PLL0 input clock duty cycle[2]	—	40	—	60	%
$f_{PLL0VCO}$	PLL0 VCO frequency	—	600	—	1250	MHz
$f_{PLL0PHI}$	PLL0 output frequency	—	4.762	—	200	MHz
$t_{PLL0LOCK}$	PLL0 lock time	—	—	—	110	µs
$\lvert\Delta_{PLL0PHISPJ}\rvert$	PLL0_PHI single period jitter f_{PLL0IN} = 20 MHz (resonator)	$f_{PLL0PHI}$ = 200 MHz, 6-sigma	—	—	200	ps
$\lvert\Delta_{PLL0PHI1SPJ}\rvert$	PLL0_PHI1 single period jitter f_{PLL0IN} = 20 MHz (resonator)	$f_{PLL0PHI1}$ = 40 MHz, 6-sigma	—	—	300[3]	ps
$\Delta_{PLL0LTJ}$	PLL0 output long term jitter[3] f_{PLL0IN} = 20 MHz (resonator), VCO frequency = 800 MHz	10 periods accumulated jitter (80 MHz equivalent frequency), 6-sigma pk-pk	—	—	±250	ps
		16 periods accumulated jitter (50 MHz equivalent frequency), 6-sigma pk-pk	—	—	±300	ps
		long term jitter (< 1 MHz equivalent frequency), 6-sigma pk-pk)	—	—	±500	ps
I_{PLL0}	PLL0 consumption	FINE LOCK state	—	—	7.5	mA

1. f_{PLL0IN} frequency must be scaled down using PLLDIG_PLL0DV[PREDIV] to ensure PFD input signal is in the range 8 MHz to 20 MHz.
2. PLL0IN clock retrieved directly from either internal IRC or external XOSC clock. Input characteristics are granted when using internal IRC or external oscillator is used in functional mode.
3. Noise on the V_{DD} supply with frequency content below 40 kHz and above 50 MHz is filtered by the PLL. Noise on the V_{DD} supply with frequency content in the range of 40 kHz – 50 MHz must be filtered externally to the device.

Table 13. PLL1 electrical characteristics

Symbol	Parameter	Conditions	Value			Unit
			Min	Typ	Max	
f_{PLL1IN}	PLL1 input clock[1]	—	38	—	78	MHz
Δ_{PLL1IN}	PLL1 input clock duty cycle[1]	—	35	—	65	%
$f_{PLL1VCO}$	PLL1 VCO frequency	—	600	—	1250	MHz
$f_{PLL1PHI}$	PLL1 output clock PHI	—	4.762	—	264	MHz
$t_{PLL1LOCK}$	PLL1 lock time	—	—	—	100	µs
$\lvert\Delta_{PLL1PHISPJ}\rvert$	PLL1_PHI single period peak-to-peak jitter	$f_{PLL1PHI}$ = 200 MHz, 6-sigma	—	—	500[2]	ps
$f_{PLL1MOD}$	PLL1 modulation frequency	—	—	—	250	kHz
$\lvert\delta_{PLL1MOD}\rvert$	PLL1 modulation depth (when enabled)	Center spread	0.25	—	2	%
		Down spread	0.5	—	4	%
I_{PLL1}	PLL1 consumption	FINE LOCK state	—	—	6	mA

1. PLL1IN clock retrieved directly from either internal PLL0 or external XOSC clock. Input characteristics are granted when using internal PLL0 or external oscillator in functional mode.
2. Noise on the V_{DD} supply with frequency content below 40 kHz and above 50 MHz is filtered by the PLL. Noise on the V_{DD} supply with frequency content in the range of 40 kHz – 50 MHz must be filtered externally to the device.

3.7.2 Oscillator electrical specifications

NOTE

All oscillator specifications in Table 14 are valid for V_{DDEH6} = 3.0 V to 5.5 V.

Table 14. External oscillator (XOSC) electrical specifications

Symbol	Parameter	Conditions	Value		Unit
			Min	Max	
f_{XTAL}	Crystal frequency range	—	8	40	MHz
t_{cst}	Crystal start-up time[1, 2]	T_J = 150 °C	—	5	ms
t_{rec}	Crystal recovery time[3]	—	—	0.5	ms
V_{IHEXT}	EXTAL input high voltage (external reference)	V_{REF} = 0.28 * V_{DDEH6}	V_{REF} + 0.6	—	V
V_{ILEXT}	EXTAL input low voltage (external reference)	V_{REF} = 0.28 * V_{DDEH6}	—	V_{REF} – 0.6	V
C_{S_EXTAL}	Total on-chip stray capacitance on EXTAL pin[4]	416-ball MAPBGA	2.3	3.0	pF
		516-ball MAPBGA	2.1	2.8	
C_{S_XTAL}	Total on-chip stray capacitance on XTAL pin[4]	416-ball MAPBGA	2.3	3.0	pF
		516-ball MAPBGA	2.2	2.9	
g_m	Oscillator transconductance[5]	Low	3	10	mA/V
		Medium	10	27	
		High	12	35	

Table continues on the next page...

Table 14. External oscillator (XOSC) electrical specifications (continued)

Symbol	Parameter	Conditions	Value		Unit
			Min	Max	
V_{EXTAL}	Oscillation amplitude on the EXTAL pin after startup[6]	—	0.5	1.6	V
V_{HYS}	Comparator hysteresis	—	0.1	1.0	V
I_{XTAL}	XTAL current[6, 7]	—	—	14	mA

1. This value is determined by the crystal manufacturer and board design.
2. Proper PC board layout procedures must be followed to achieve specifications.
3. Crystal recovery time is the time for the oscillator to settle to the correct frequency after adjustment of the integrated load capacitor value.
4. See crystal manufacturer's specification for recommended load capacitor (C_L) values.The external oscillator requires external load capacitors when operating in a "low" transconductance range. Account for on-chip stray capacitance (C_{S_EXTAL}/C_{S_XTAL}) and PCB capacitance when selecting a load capacitor value. When operating in a "medium" or "high" transconductance range, the integrated load capacitor value is selected via software to match the crystal manufacturer's specification, while accounting for on-chip and PCB capacitance.
5. Select a "low," "medium," or "high" setting using the UTEST Miscellaneous DCF client's XOSC_LF_EN and XOSC_EN_HIGH fields. "Low" is the setting commonly used for crystals at 8 MHz, "medium" is commonly used for crystals greater than 8 MHz to 20 MHz, and "high" is commonly used for crystals greater than 20 MHz to 40 MHz. However, the user must characterize carefully to determine the best g_m setting for the intended application because crystal load capacitance, board layout, and other factors affect the g_m value that is needed. The user may need an additional Rshunt to optimize g_m depending on the system environment. Use of overtone crystals is not recommended.
6. Amplitude on the EXTAL pin after startup is determined by the ALC block (that is, the Automatic Level Control Circuit). The function of the ALC is to provide high drive current during oscillator startup, while reducing current after oscillation to reduce power, distortion, and RFI, and to avoid over-driving the crystal. The operating point of the ALC is dependent on the crystal value and loading conditions.
7. I_{XTAL} is the oscillator bias current out of the XTAL pin with both EXTAL and XTAL pins grounded. This is the maximum current during startup of the oscillator. The current after oscillation is typically in the 2–3 mA range and is dependent on the load and series resistance of the crystal. Test circuit is shown in Figure 7.

Table 15. Selectable load capacitance

load_cap_sel[4:0] from DCF record	Load capacitance[1, 2] (pF)
00000	1.8
00001	2.8
00010	3.7
00011	4.6
00100	5.6
00101	6.5
00110	7.4
00111	8.4
01000	9.3
01001	10.2
01010	11.2
01011	12.1
01100	13.0
01101	13.9

Table continues on the next page...

Table 15. Selectable load capacitance (continued)

load_cap_sel[4:0] from DCF record	Load capacitance[1, 2] (pF)
01110	14.9
01111	15.8

1. Values are determined from simulation across process corners and voltage and temperature variation. Capacitance values vary ±12% across process, 0.25% across voltage, and no variation across temperature.
2. Values in this table do not include the die and package capacitances given by C_{S_XTAL}/C_{S_EXTAL} in Table 14.

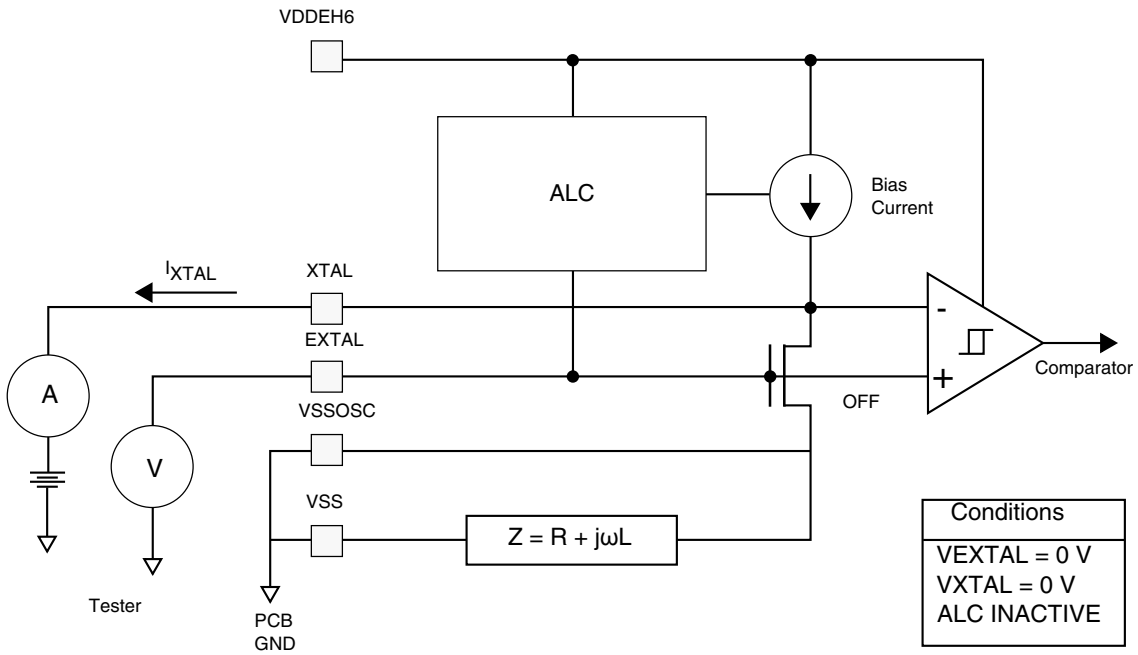

Figure 7. Test circuit

Table 16. Internal RC (IRC) oscillator electrical specifications

Symbol	Parameter	Conditions	Value			Unit
			Min	Typ	Max	
f_{Target}	IRC target frequency	—	—	16	—	MHz
δf_{var_T}	IRC frequency variation	T < 150 °C	–8	—	8	%

3.8 Analog-to-Digital Converter (ADC) electrical specifications

3.8.1 Enhanced Queued Analog-to-Digital Converter (eQADC)

Table 17. eQADC conversion specifications (operating)

Symbol	Parameter	Value		Unit
		Min	Max	
f_{ADCLK}	ADC Clock (ADCLK) Frequency	2	33	MHz
CC	Conversion Cycles	2 + 13	128 + 15	ADCLK cycles
T_{SR}	Stop Mode Recovery Time[1]	10	—	µs
—	Resolution[2]	1.25	—	mV
INL	INL: 16.5 MHz eQADC clock[3]	–4	4	LSB[4]
	INL: 33 MHz eQADC clock[3]	–6	6	LSB
DNL	DNL: 16.5 MHz eQADC clock[3]	–3	3	LSB
	DNL: 33 MHz eQADC clock[3]	–3	3	LSB
OFFNC	Offset Error without Calibration	0	140	LSB
OFFWC	Offset Error with Calibration	–8	8	LSB
GAINNC	Full Scale Gain Error without Calibration	–150	0	LSB
GAINWC	Full Scale Gain Error with Calibration	–8	8	LSB
I_{INJ}	Disruptive Input Injection Current[5, 6, 7, 8]	–3	3	mA
E_{INJ}	Incremental Error due to injection current[9, 10]	—	+4	Counts
TUE	TUE value[11, 12] (with calibration)	—	±8	Counts
GAINVGA1	Variable gain amplifier accuracy (gain = 1)[13]	-	-	Counts[15]
	INL, 16.5 MHz ADC	–4	4	
	INL, 33 MHz ADC	–8	8	
	DNL, 16.5 MHz ADC	–3[14]	3[14]	
	DNL, 33 MHz ADC	–3[14]	3[14]	
GAINVGA2	Variable gain amplifier accuracy (gain = 2)[13]	-	-	Counts
	INL, 16.5 MHz ADC	–5	5	
	INL, 33 MHz ADC	–8	8	
	DNL, 16.5 MHz ADC	–3	3	
	DNL, 33 MHz ADC	–3	3	
GAINVGA4	Variable gain amplifier accuracy (gain = 4)[13]	-	-	Counts
	INL, 16.5 MHz ADC	–7	7	
	INL, 33 MHz ADC	–8	8	
	DNL, 16.5 MHz ADC	–4	4	
	DNL, 33 MHz ADC	–4	4	
I_{ADC}	Current consumption per ADC (two ADCs per EQADC)	—	10	mA
I_{ADR}	Reference voltage current consumption per EQADC	—	200	µA

1. Stop mode recovery time is the time from the setting of either of the enable bits in the ADC Control Register to the time that the ADC is ready to perform conversions.Delay from power up to full accuracy = 8 ms.
2. At $V_{RH\_EQ} - V_{RL\_EQ}$ = 5.12 V, one count = 1.25 mV without using pregain. Based on 12-bit conversion result; does not account for AC and DC errors
3. INL and DNL are tested from V_{RL} + 50 LSB to V_{RH} – 50 LSB.
4. At $V_{RH\_EQ} - V_{RL\_EQ}$ = 5.12 V, one LSB = 1.25 mV.

5. Below disruptive current conditions, the channel being stressed has conversion values of $3FF for analog inputs greater than V_{RH} and $000 for values less than V_{RL}. Other channels are not affected by non-disruptive conditions.
6. Exceeding limit may cause conversion error on stressed channels and on unstressed channels. Transitions within the limit do not affect device reliability or cause permanent damage.
7. Input must be current limited to the value specified. To determine the value of the required current-limiting resistor, calculate resistance values using $V_{POSCLAMP} = V_{DDA} + 0.5$ V and $V_{NEGCLAMP} = -0.3$ V, then use the larger of the calculated values.
8. Condition applies to two adjacent pins at injection limits.
9. Performance expected with production silicon.
10. All channels have same 10 kΩ < Rs < 100 kΩ Channel under test has Rs = 10 kΩ, $I_{INJ}=I_{INJMAX},I_{INJMIN}$.
11. The TUE specification is always less than the sum of the INL, DNL, offset, and gain errors due to cancelling errors.
12. TUE does not apply to differential conversions.
13. Variable gain is controlled by setting the PRE_GAIN bits in the ADC_ACR1-8 registers to select a gain factor of ×1, ×2, or ×4. Settings are for differential input only. Tested at ×1 gain. Values for other settings are guaranteed as indicated.
14. Guaranteed 10-bit monotonicity.
15. At $V_{RH\_EQ} - V_{RL\_EQ} = 5.12$ V, one LSB = 1.25 mV.

3.8.2 Sigma-Delta ADC (SDADC)

The SDADC is a 16-bit Sigma-Delta analog-to-digital converter with a 333 Ksps maximum output conversion rate.

NOTE

The voltage range is 4.5 V to 5.5 V for SDADC specifications, except where noted otherwise.

Table 18. SDADC electrical specifications

Symbol	Parameter	Conditions	Value			Unit
			Min	Typ	Max	
V_{IN}	ADC input signal	—	0	—	V_{DDA_SD}	V
V_{IN_PK2PK}[1]	Input range peak to peak $V_{IN\_PK2PK} = V_{INP}$[2] – V_{INM},[3]	Single ended $V_{INM} = V_{RL\_SD}$	V_{RH_SD}/GAIN			V
		Single ended $V_{INM} = 0.5*V_{RH\_SD}$ GAIN = 1	±0.5*V_{RH_SD}			
		Single ended $V_{INM} = 0.5*V_{RH\_SD}$ GAIN = 2,4,8,16	±V_{RH_SD}/GAIN			
		Differential $0 < V_{IN} < V_{DDEx}$	±V_{RH_SD}/GAIN			
f_{ADCD_M}	SD clock frequency[4]	—	4	14.4	16	MHz
f_{ADCD_S}	Conversion rate	—	—	—	333	Ksps
—	Oversampling ratio	Internal modulator	24	—	256	—
RESOLUTION	SD register resolution[5]	2's complement notation	16			bit

Table continues on the next page...